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Applications of "[Embedded - Microcontrollers](#)"

Details

Product Status	Active
Core Processor	ARM® Cortex®-M4
Core Size	32-Bit Single-Core
Speed	100MHz
Connectivity	I ² C, IrDA, LINbus, MMC/SD/SDIO, SPI, UART/USART, USB OTG
Peripherals	Brown-out Detect/Reset, DMA, I ² S, POR, PWM, WDT
Number of I/O	50
Program Memory Size	256KB (256K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	128K x 8
Voltage - Supply (Vcc/Vdd)	1.7V ~ 3.6V
Data Converters	A/D 16x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32f411rct6

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2 Description

The STM32F411xC/xE devices are based on the high-performance ARM® Cortex®-M4 32-bit RISC core operating at a frequency of up to 100 MHz. The Cortex®-M4 core features a Floating point unit (FPU) single precision which supports all ARM single-precision data-processing instructions and data types. It also implements a full set of DSP instructions and a memory protection unit (MPU) which enhances application security.

The STM32F411xC/xE belongs to the STM32 Dynamic Efficiency™ product line (with products combining power efficiency, performance and integration) while adding a new innovative feature called Batch Acquisition Mode (BAM) allowing to save even more power consumption during data batching.

The STM32F411xC/xE incorporate high-speed embedded memories (up to 512 Kbytes of Flash memory, 128 Kbytes of SRAM), and an extensive range of enhanced I/Os and peripherals connected to two APB buses, two AHB bus and a 32-bit multi-AHB bus matrix.

All devices offer one 12-bit ADC, a low-power RTC, six general-purpose 16-bit timers including one PWM timer for motor control, two general-purpose 32-bit timers. They also feature standard and advanced communication interfaces.

- Up to three I²Cs
- Five SPIs
- Five I²Ss out of which two are full duplex. To achieve audio class accuracy, the I²S peripherals can be clocked via a dedicated internal audio PLL or via an external clock to allow synchronization.
- Three USARTs
- SDIO interface
- USB 2.0 OTG full speed interface

Refer to [Table 2: STM32F411xC/xE features and peripheral counts](#) for the peripherals available for each part number.

The STM32F411xC/xE operate in the - 40 to + 125 °C temperature range from a 1.7 (PDR OFF) to 3.6 V power supply. A comprehensive set of power-saving mode allows the design of low-power applications.

These features make the STM32F411xC/xE microcontrollers suitable for a wide range of applications:

- Motor drive and application control
- Medical equipment
- Industrial applications: PLC, inverters, circuit breakers
- Printers, and scanners
- Alarm systems, video intercom, and HVAC
- Home audio appliances
- Mobile phone sensor hub

[Figure 3](#) shows the general block diagram of the devices.

3.15 Power supply supervisor

3.15.1 Internal reset ON

This feature is available for V_{DD} operating voltage range 1.8 V to 3.6 V.

The internal power supply supervisor is enabled by holding PDR_ON high.

The devices have an integrated power-on reset (POR) / power-down reset (PDR) circuitry coupled with a Brownout reset (BOR) circuitry. At power-on, POR is always active, and ensures proper operation starting from 1.8 V. After the 1.8 V POR threshold level is reached, the option byte loading process starts, either to confirm or modify default thresholds, or to disable BOR permanently. Three BOR thresholds are available through option bytes.

The devices remain in reset mode when V_{DD} is below a specified threshold, $V_{POR/PDR}$ or V_{BOR} , without the need for an external reset circuit.

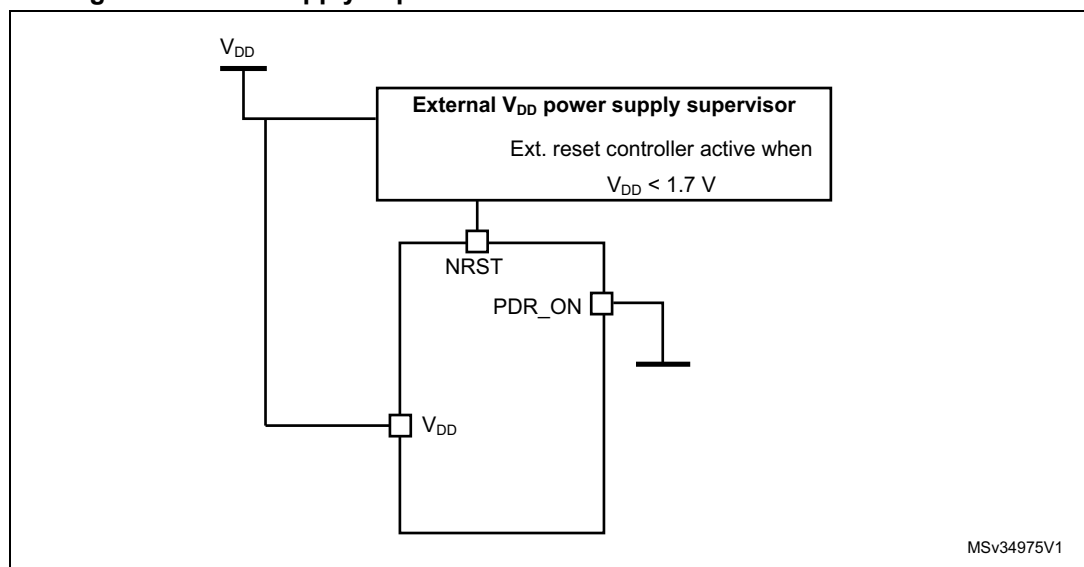
The devices also feature an embedded programmable voltage detector (PVD) that monitors the V_{DD}/V_{DDA} power supply and compares it to the V_{PVD} threshold. An interrupt can be generated when V_{DD}/V_{DDA} drops below the V_{PVD} threshold and/or when V_{DD}/V_{DDA} is higher than the V_{PVD} threshold. The interrupt service routine can then generate a warning message and/or put the MCU into a safe state. The PVD is enabled by software.

3.15.2 Internal reset OFF

This feature is available only on packages featuring the PDR_ON pin. The internal power-on reset (POR) / power-down reset (PDR) circuitry is disabled by setting the PDR_ON pin to low.

An external power supply supervisor should monitor V_{DD} and should set the device in reset mode when V_{DD} is below 1.7 V. NRST should be connected to this external power supply supervisor. Refer to [Figure 5: Power supply supervisor interconnection with internal reset OFF](#).

Figure 5. Power supply supervisor interconnection with internal reset OFF⁽¹⁾



1. The PRD_ON pin is only available on the WLCSP49 and UFBGA100 packages.

A comprehensive set of power-saving mode allows to design low-power applications.

When the internal reset is OFF, the following integrated features are no longer supported:

- The integrated power-on reset (POR) / power-down reset (PDR) circuitry is disabled.
- The brownout reset (BOR) circuitry must be disabled.
- The embedded programmable voltage detector (PVD) is disabled.
- V_{BAT} functionality is no more available and VBAT pin should be connected to V_{DD} .

3.16 Voltage regulator

The regulator has four operating modes:

- Regulator ON
 - Main regulator mode (MR)
 - Low power regulator (LPR)
 - Power-down
- Regulator OFF

3.16.1 Regulator ON

On packages embedding the BYPASS_REG pin, the regulator is enabled by holding BYPASS_REG low. On all other packages, the regulator is always enabled.

There are three power modes configured by software when the regulator is ON:

- MR is used in the nominal regulation mode (With different voltage scaling in Run)
In Main regulator mode (MR mode), different voltage scaling are provided to reach the best compromise between maximum frequency and dynamic power consumption.
- LPR is used in the Stop modes
The LP regulator mode is configured by software when entering Stop mode.
- Power-down is used in Standby mode.
The Power-down mode is activated only when entering in Standby mode. The regulator output is in high impedance and the kernel circuitry is powered down, inducing zero consumption. The contents of the registers and SRAM are lost.

Depending on the package, one or two external ceramic capacitors should be connected on the V_{CAP_1} and V_{CAP_2} pins. The V_{CAP_2} pin is only available for the LQFP100 and UFBGA100 packages.

All packages have the regulator ON feature.

3.16.2 Regulator OFF

The Regulator OFF is available only on the UFBGA100, which features the BYPASS_REG pin. The regulator is disabled by holding BYPASS_REG high. The regulator OFF mode allows to supply externally a V12 voltage source through V_{CAP_1} and V_{CAP_2} pins.

Since the internal voltage scaling is not managed internally, the external voltage value must be aligned with the targeted maximum frequency. Refer to [Table 14: General operating conditions](#).

The two 2.2 μF V_{CAP} ceramic capacitors should be replaced by two 100 nF decoupling capacitors. Refer to [Figure 17: Power supply scheme](#).

Table 6. USART feature comparison

USART name	Standard features	Modem (RTS/CTS)	LIN	SPI master	IrDA	Smartcard (ISO 7816)	Max. baud rate in Mbit/s (oversampling by 16)	Max. baud rate in Mbit/s (oversampling by 8)	APB mapping
USART1	X	X	X	X	X	X	6.25	12.5	APB2 (max. 100 MHz)
USART2	X	X	X	X	X	X	3.12	6.25	APB1 (max. 50 MHz)
USART6	X	N.A	X	X	X	X	6.25	12.5	APB2 (max. 100 MHz)

3.23 Serial peripheral interface (SPI)

The devices feature five SPIs in slave and master modes in full-duplex and simplex communication modes. SPI1, SPI4 and SPI5 can communicate at up to 50 Mbit/s, SPI2 and SPI3 can communicate at up to 25 Mbit/s. The 3-bit prescaler gives 8 master mode frequencies and the frame is configurable to 8 bits or 16 bits. The hardware CRC generation/verification supports basic SD Card/MMC modes. All SPIs can be served by the DMA controller.

The SPI interface can be configured to operate in TI mode for communications in master mode and slave mode.

3.24 Inter-integrated sound (I²S)

Five standard I²S interfaces (multiplexed with SPI1 to SPI5) are available. They can be operated in master or slave mode, in simplex communication modes and full duplex for I2S2 and I2S3 and can be configured to operate with a 16-/32-bit resolution as an input or output channel. All the I2Sx audio sampling frequencies from 8 kHz up to 192 kHz are supported. When either or both of the I²S interfaces is/are configured in master mode, the master clock can be output to the external DAC/CODEC at 256 times the sampling frequency.

All I²Sx can be served by the DMA controller.

3.25 Audio PLL (PLLI2S)

The devices feature an additional dedicated PLL for audio I²S application. It allows to achieve error-free I²S sampling clock accuracy without compromising on the CPU performance.

The PLLI2S configuration can be modified to manage an I²S sample rate change without disabling the main PLL (PLL) used for the CPU.

The audio PLL can be programmed with very low error to obtain sampling rates ranging from 8 kHz to 192 kHz.

Table 8. STM32F411xC/xE pin definitions (continued)

Pin number					Pin name (function after reset) ⁽¹⁾	Pin type	I/O structure	Notes	Alternate functions	Additional functions
UFQFPN48	LQFP64	WLCSP49	LQFP100	UFBGA100						
-	-	-	81	C9	PD0	I/O	FT	-	EVENTOUT	-
-	-	-	82	B9	PD1	I/O	FT	-	EVENTOUT	-
-	54	-	83	C8	PD2	I/O	FT	-	TIM3_ETR, SDIO_CMD, EVENTOUT	-
-	-	-	84	B8	PD3	I/O	FT	-	SPI2_SCK/I2S2_CK, USART2_CTS, EVENTOUT	-
-	-	-	85	B7	PD4	I/O	FT	-	USART2_RTS, EVENTOUT	-
-	-	-	86	A6	PD5	I/O	FT	-	USART2_TX, EVENTOUT	-
-	-	-	87	B6	PD6	I/O	FT	-	SPI3_MOSI/I2S3_SD, USART2_RX, EVENTOUT	-
-	-	-	88	A5	PD7	I/O	FT	-	USART2_CK, EVENTOUT	-
39	55	A3	89	A8	PB3	I/O	FT	-	JTDO-SWO, TIM2_CH2, SPI1_SCK/I2S1_CK, SPI3_SCK/I2S3_CK, USART1_RX, I2C2_SDA, EVENTOUT	-
40	56	A4	90	A7	PB4	I/O	FT	-	JTRST, TIM3_CH1, SPI1_MISO, SPI3_MISO, I2S3ext_SD, I2C3_SDA, SDIO_D0, EVENTOUT	-
41	57	B4	91	C5	PB5	I/O	TC	-	TIM3_CH2, I2C1_SMBA, SPI1_MOSI/I2S1_SD, SPI3_MOSI/I2S3_SD, SDIO_D3, EVENTOUT	-
42	58	C4	92	B5	PB6	I/O	FT	-	TIM4_CH1, I2C1_SCL, USART1_TX, EVENTOUT	-



Table 9. Alternate function mapping (continued)

Port	AF00	AF01	AF02	AF03	AF04	AF05	AF06	AF07	AF08	AF09	AF10	AF11	AF12	AF13	AF14	AF15
	SYS_AF	TIM1/TIM2	TIM3/ TIM4/ TIM5	TIM9/ TIM10/ TIM11	I2C1/I2C2/ I2C3	SPI1/I2S1S PI2/ I2S2/SPI3/ I2S3	SPI2/I2S2/ SPI3/ I2S3/SPI4/ I2S4/SPI5/ I2S5	SPI3/I2S3/ USART1/ USART2	USART6	I2C2/ I2C3	OTG1_FS		SDIO			
Port B	PB0	-	TIM1_CH2N	TIM3_CH3	-	-	-	SPI5_SCK /I2S5_CK	-	-	-	-	-	-	-	EVENT OUT
	PB1	-	TIM1_CH3N	TIM3_CH4	-	-	-	SPI5_NSS /I2S5_WS	-	-	-	-	-	-	-	EVENT OUT
	PB2	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
	PB3	JTDO- SWO	TIM2_CH2	-	-	-	SPI1_SCK/ 2S1_CK	SPI3_SCK /I2S3_CK	USART1_ RX	-	I2C2_SDA	-	-	-	-	EVENT OUT
	PB4	JTRST		TIM3_CH1	-	-	SPI1_MISO	SPI3_MISO	I2S3ext_S D	-	I2C3_SDA			SDIO_ D0	-	EVENT OUT
	PB5	-	-	TIM3_CH2	-	I2C1_SMB A	SPI1_MOSI /I2S1_SD	SPI3_MOSI/ I2S3_SD		-	-	-	-	SDIO_ D3	-	EVENT OUT
	PB6	-	-	TIM4_CH1	-	I2C1_SCL	-	-	USART1_ TX	-	-	-	-		-	EVENT OUT
	PB7	-	-	TIM4_CH2	-	I2C1_SDA	-	-	USART1_ RX	-	-	-	-	SDIO_ D0	-	EVENT OUT
	PB8	-	-	TIM4_CH3	TIM10_CH1	I2C1_SCL	-	SPI5_MOSI/ I2S5_SD	-	-	I2C3_SDA	-	-	SDIO_ D4	-	EVENT OUT
	PB9	-	-	TIM4_CH4	TIM11_CH1	I2C1_SDA	SPI2_NSS/ 2S2_WS	-	-	-	I2C2_SDA	-	-	SDIO_ D5	-	EVENT OUT
	PB10	-	TIM2_CH3	-	-	I2C2_SCL	SPI2_SCK/ 2S2_CK	I2S3_MCK	-	-	-	-	-	SDIO_ D7	-	EVENT OUT
	PB11	-	TIM2_CH4	-	-	I2C2_SDA	I2S2_CKIN	-	-	-	-	-	-	-	-	EVENT OUT
	PB12	-	TIM1_BKIN	-	-	I2C2_SMB A	SPI2_NSS/ 2S2_WS	SPI4_NSS /I2S4_WS	SPI3_SCK /I2S3_CK	-	-	-	-	-	-	EVENT OUT
	PB13	-	TIM1_CH1N	-	-	-	SPI2_SCK/ 2S2_CK	SPI4_SCK/ I2S4_CK	-	-	-	-	-	-	-	EVENT OUT
	PB14	-	TIM1_CH2N	-	-	-	SPI2_MISO	I2S2ext_SD	-	-	-	-	-	SDIO_ D6	-	EVENT OUT
	PB15	RTC_50H Z	TIM1_CH3N	-	-	-	SPI2_MOSI /I2S2_SD	-	-	-	-	-	-	SDIO_ CK	-	EVENT OUT



Table 9. Alternate function mapping (continued)

Port	AF00	AF01	AF02	AF03	AF04	AF05	AF06	AF07	AF08	AF09	AF10	AF11	AF12	AF13	AF14	AF15
	SYS_AF	TIM1/TIM2	TIM3/ TIM4/ TIM5	TIM9/ TIM10/ TIM11	I2C1/I2C2/ I2C3	SPI1/I2S1S PI2/ I2S2/SPI3/ I2S3	SPI2/I2S2/ SPI3/ I2S3/SPI4/ I2S4/SPI5/ I2S5	SPI3/I2S3/ USART1/ USART2	USART6	I2C2/ I2C3	OTG1_FS		SDIO			
Port D	PD0	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
	PD1	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
	PD2	-	-	TIM3_ETR	-	-	-	-	-	-	-	-	SDIO_ CMD			EVENT OUT
	PD3	-	-	-	-	SPI2_SCK/ I2S2_CK		USART2_ CTS	-	-	-	-	-	-	-	EVENT OUT
	PD4	-	-	-	-	-	-	USART2_ RTS	-	-	-	-	-	-	-	EVENT OUT
	PD5	-	-	-	-	-	-	USART2_ TX	-	-	-	-	-	-	-	EVENT OUT
	PD6	-	-	-	-	SPI3_MOSI /I2S3_SD	-	USART2_ RX	-	-	-	-	-	-	-	EVENT OUT
	PD7	-	-	-	-	-	-	USART2_ CK	-	-	-	-	-	-	-	EVENT OUT
	PD8	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
	PD9	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
	PD10	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
	PD11	-	-	-	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
	PD12	-	-	TIM4_CH1	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
	PD13	-	-	TIM4_CH2	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
	PD14	-	-	TIM4_CH3	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT
	PD15	-	-	TIM4_CH4	-	-	-	-	-	-	-	-	-	-	-	EVENT OUT

**Table 10. STM32F411xC/xE
register boundary addresses (continued)**

Bus	Boundary address	Peripheral
AHB2	0x5000 0000 - 0x5003 FFFF	USB OTG FS
AHB1	0x4002 6800 - 0x4FFF FFFF	Reserved
	0x4002 6400 - 0x4002 67FF	DMA2
	0x4002 6000 - 0x4002 63FF	DMA1
	0x4002 5000 - 0x4002 4FFF	Reserved
	0x4002 3C00 - 0x4002 3FFF	Flash interface register
	0x4002 3800 - 0x4002 3BFF	RCC
	0x4002 3400 - 0x4002 37FF	Reserved
	0x4002 3000 - 0x4002 33FF	CRC
	0x4002 2000 - 0x4002 2FFF	Reserved
	0x4002 1C00 - 0x4002 1FFF	GPIOH
	0x4002 1400 - 0x4002 1BFF	Reserved
	0x4002 1000 - 0x4002 13FF	GPIOE
	0x4002 0C00 - 0x4002 0FFF	GIPOD
	0x4002 0800 - 0x4002 0BFF	GPIOC
	0x4002 0400 - 0x4002 07FF	GPIOB
	0x4002 0000 - 0x4002 03FF	GPIOA

6.1.5 Pin input voltage

The input voltage measurement on a pin of the device is described in [Figure 16](#).

Figure 16. Input voltage measurement

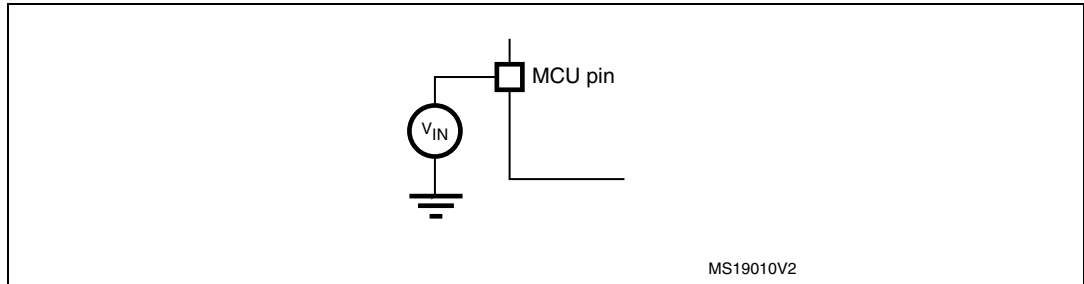


Table 28. Typical and maximum current consumption in Stop mode - $V_{DD}=3.6\text{ V}$

Symbol	Conditions	Parameter	Typ	Max ⁽¹⁾					Unit
			T _A = 25 °C	T _A = 25 °C	T _A = 85 °C	T _A = 105 °C	T _A = 125 °C		
I _{DD_STOP}	Flash in Stop mode, all oscillators OFF, no independent watchdog	Main regulator usage	113.7	145 ⁽²⁾	410	720 ⁽²⁾	1217	µA	
		Low power regulator usage	43.1	68 ⁽²⁾	310	600 ⁽²⁾	1073		
	Flash in Deep power down mode, all oscillators OFF, no independent watchdog	Main regulator usage	76.2	105 ⁽²⁾	320	600 ⁽²⁾	1019		
		Low power regulator usage	14	38 ⁽²⁾	275	560 ⁽²⁾	1025		
		Low power low voltage regulator usage	10	30 ⁽²⁾	235	510 ⁽²⁾	928		

1. Guaranteed by characterization results.

2. Guaranteed by test in production.

Table 29. Typical and maximum current consumption in Standby mode - $V_{DD}=1.7\text{ V}$

Symbol	Parameter	Conditions	Typ ⁽¹⁾	Max ⁽²⁾				Unit
			T _A = 25 °C	T _A = 25 °C	T _A = 85 °C	T _A = 105 °C	T _A = 125 °C	
I _{DD_STBY}	Supply current in Standby mode	Low-speed oscillator (LSE) and RTC ON	2.4	4	12	25	50	μA
		RTC and LSE OFF	1.8	3 ⁽³⁾	11	24 ⁽³⁾	49	

1. When the PDR is OFF (internal reset is OFF), the typical current consumption is reduced by 1.2 μA .

2. Guaranteed by characterization results.

3. Guaranteed by test in production.

Table 30. Typical and maximum current consumption in Standby mode - $V_{DD}=3.6\text{ V}$

Symbol	Parameter	Conditions	Typ ⁽¹⁾	Max ⁽²⁾				Unit
			T _A = 25 °C	T _A = 25 °C	T _A = 85 °C	T _A = 105 °C	T _A = 125 °C	
I _{DD_STBY}	Supply current in Standby mode	Low-speed oscillator (LSE) and RTC ON	2.8	5	14	29	59	μA
		RTC and LSE OFF	2.1	4 ⁽³⁾	13.5	28 ⁽³⁾	58	

1. When the PDR is OFF (internal reset is OFF), the typical current consumption is reduced by 1.2 μA .

2. Guaranteed by characterization results.

3. Guaranteed by test in production.

Table 41. Main PLL characteristics (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$I_{DD(PLL)}^{(4)}$	PLL power consumption on VDD	VCO freq = 100 MHz VCO freq = 432 MHz	0.15 0.45	-	0.40 0.75	mA
$I_{DDA(PLL)}^{(4)}$	PLL power consumption on VDDA	VCO freq = 100 MHz VCO freq = 432 MHz	0.30 0.55	-	0.40 0.85	

1. Take care of using the appropriate division factor M to obtain the specified PLL input clock values. The M factor is shared between PLL and PLLI2S.
2. Guaranteed by design.
3. The use of two PLLs in parallel could degraded the Jitter up to +30%.
4. Guaranteed by characterization results.

Table 42. PLLI2S (audio PLL) characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{PLLI2S_IN}	PLLI2S input clock ⁽¹⁾	-	0.95 ⁽²⁾	1	2.10	MHz
f_{PLLI2S_OUT}	PLLI2S multiplier output clock	-	-	-	216	
f_{VCO_OUT}	PLLI2S VCO output	-	100	-	432	
t_{LOCK}	PLLI2S lock time	VCO freq = 100 MHz	75	-	200	μs
		VCO freq = 432 MHz	100	-	300	
Jitter ⁽³⁾	Master I2S clock jitter	Cycle to cycle at 12.288 MHz on 48 kHz period, N=432, R=5	RMS	-	90	ps
			peak to peak	-	±280	
	WS I2S clock jitter	Average frequency of 12.288 MHz N = 432, R = 5 on 1000 samples	-	90	-	
		Cycle to cycle at 48 KHz on 1000 samples	-	400	-	
$I_{DD(PLLI2S)}^{(4)}$	PLLI2S power consumption on VDD	VCO freq = 100 MHz VCO freq = 432 MHz	0.15 0.45	-	0.40 0.75	mA
$I_{DDA(PLLI2S)}^{(4)}$	PLLI2S power consumption on VDDA	VCO freq = 100 MHz VCO freq = 432 MHz	0.30 0.55	-	0.40 0.85	

1. Take care of using the appropriate division factor M to have the specified PLL input clock values.
2. Guaranteed by design.
3. Value given with main PLL running.
4. Guaranteed by characterization results.

Table 45. Flash memory programming

Symbol	Parameter	Conditions	Min ⁽¹⁾	Typ	Max ⁽¹⁾	Unit
t_{prog}	Word programming time	Program/erase parallelism (PSIZE) = x 8/16/32	-	16	100 ⁽²⁾	μs
$t_{\text{ERASE16KB}}$	Sector (16 KB) erase time	Program/erase parallelism (PSIZE) = x 8	-	400	800	ms
		Program/erase parallelism (PSIZE) = x 16	-	300	600	
		Program/erase parallelism (PSIZE) = x 32	-	250	500	
$t_{\text{ERASE64KB}}$	Sector (64 KB) erase time	Program/erase parallelism (PSIZE) = x 8	-	1200	2400	ms
		Program/erase parallelism (PSIZE) = x 16	-	700	1400	
		Program/erase parallelism (PSIZE) = x 32	-	550	1100	
$t_{\text{ERASE128KB}}$	Sector (128 KB) erase time	Program/erase parallelism (PSIZE) = x 8	-	2	4	s
		Program/erase parallelism (PSIZE) = x 16	-	1.3	2.6	
		Program/erase parallelism (PSIZE) = x 32	-	1	2	
t_{ME}	Mass erase time	Program/erase parallelism (PSIZE) = x 8	-	8	16	s
		Program/erase parallelism (PSIZE) = x 16	-	5.5	11	
		Program/erase parallelism (PSIZE) = x 32	-	4	8	
V_{prog}	Programming voltage	32-bit program operation	2.7	-	3.6	V
		16-bit program operation	2.1	-	3.6	V
		8-bit program operation	1.7	-	3.6	V

1. Guaranteed by characterization results.

2. The maximum programming time is measured after 100K erase operations.

Table 46. Flash memory programming with V_{PP} voltage

Symbol	Parameter	Conditions	Min ⁽¹⁾	Typ	Max ⁽¹⁾	Unit
t_{prog}	Double word programming	$T_{\text{A}} = 0 \text{ to } +40 \text{ }^{\circ}\text{C}$ $V_{\text{DD}} = 3.3 \text{ V}$ $V_{\text{PP}} = 8.5 \text{ V}$	-	16	100 ⁽²⁾	μs
$t_{\text{ERASE16KB}}$	Sector (16 KB) erase time		-	230	-	ms
$t_{\text{ERASE64KB}}$	Sector (64 KB) erase time		-	490	-	
$t_{\text{ERASE128KB}}$	Sector (128 KB) erase time		-	875	-	
t_{ME}	Mass erase time		-	3.50	-	s

Output voltage levels

Unless otherwise specified, the parameters given in [Table 54](#) are derived from tests performed under ambient temperature and V_{DD} supply voltage conditions summarized in [Table 14](#). All I/Os are CMOS and TTL compliant.

Table 54. Output voltage characteristics

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{OL}^{(1)}$	Output low level voltage for an I/O pin	CMOS port ⁽²⁾ $I_{IO} = +8 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	0.4	V
$V_{OH}^{(3)}$	Output high level voltage for an I/O pin		$V_{DD}-0.4$	-	
$V_{OL}^{(1)}$	Output low level voltage for an I/O pin	TTL port ⁽²⁾ $I_{IO} = +8 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	0.4	V
$V_{OH}^{(3)}$	Output high level voltage for an I/O pin		2.4	-	
$V_{OL}^{(1)}$	Output low level voltage for an I/O pin	$I_{IO} = +20 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	$1.3^{(4)}$	V
$V_{OH}^{(3)}$	Output high level voltage for an I/O pin		$V_{DD}-1.3^{(4)}$	-	
$V_{OL}^{(1)}$	Output low level voltage for an I/O pin	$I_{IO} = +6 \text{ mA}$ $1.8 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	$0.4^{(4)}$	V
$V_{OH}^{(3)}$	Output high level voltage for an I/O pin		$V_{DD}-0.4^{(4)}$	-	
$V_{OL}^{(1)}$	Output low level voltage for an I/O pin	$I_{IO} = +4 \text{ mA}$ $1.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	$0.4^{(5)}$	V
$V_{OH}^{(3)}$	Output high level voltage for an I/O pin		$V_{DD}-0.4^{(5)}$	-	

1. The I_{IO} current sunk by the device must always respect the absolute maximum rating specified in [Table 12](#) and the sum of I_{IO} (I/O ports and control pins) must not exceed I_{VSS} .
2. TTL and CMOS outputs are compatible with JEDEC standards JESD36 and JESD52.
3. The I_{IO} current sourced by the device must always respect the absolute maximum rating specified in [Table 12](#) and the sum of I_{IO} (I/O ports and control pins) must not exceed I_{VDD} .
4. Guaranteed by characterization results.
5. Guaranteed by design.

SPI interface characteristics

Unless otherwise specified, the parameters given in [Table 60](#) for the SPI interface are derived from tests performed under the ambient temperature, f_{PCLKx} frequency and V_{DD} supply voltage conditions summarized in [Table 14](#), with the following configuration:

- Output speed is set to OSPEEDRy[1:0] = 10
- Capacitive load C = 30 pF
- Measurement points are done at CMOS levels: $0.5V_{DD}$

Refer to [Section 6.3.16: I/O port characteristics](#) for more details on the input/output alternate function characteristics (NSS, SCK, MOSI, MISO for SPI).

Table 60. SPI dynamic characteristics⁽¹⁾

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{SCK} $1/t_{c(SCK)}$	SPI clock frequency	Master full duplex/receiver mode, $2.7\text{ V} < V_{DD} < 3.6\text{ V}$ SPI1/4/5	-	-	42	MHz
		Master full duplex/receiver mode, $3.0\text{ V} < V_{DD} < 3.6\text{ V}$ SPI1/4/5	-	-	50	
		Master transmitter mode $1.7\text{ V} < V_{DD} < 3.6\text{ V}$ SPI1/4/5	-	-	50	
		Master mode $1.7\text{ V} < V_{DD} < 3.6\text{ V}$ SPI1/2/3/4/5	-	-	25	
		Slave transmitter/full duplex mode $2.7\text{ V} < V_{DD} < 3.6\text{ V}$ SPI1/4/5	-	-	$38^{(2)}$	
		Slave receiver mode, $1.8\text{ V} < V_{DD} < 3.6\text{ V}$ SPI1/4/5	-	-	50	
		Slave mode, $1.8\text{ V} < V_{DD} < 3.6\text{ V}$ SPI1/2/3/4/5	-	-	25	
Duty(SCK)	Duty cycle of SPI clock frequency	Slave mode	30	50	70	%
$t_{w(SCKH)}$ $t_{w(SCKL)}$	SCK high and low time	Master mode, SPI presc = 2	$T_{PCLK}-1.5$	T_{PCLK}	$T_{PCLK}+1.5$	ns
$t_{su(NSS)}$	NSS setup time	Slave mode, SPI presc = 2	$3T_{PCLK}$	-	-	ns
$t_{h(NSS)}$	NSS hold time	Slave mode, SPI presc = 2	$2T_{PCLK}$	-	-	ns
$t_{su(MI)}$	Data input setup time	Master mode	4	-	-	ns
$t_{su(SI)}$		Slave mode	2.5	-	-	ns
$t_{h(MI)}$	Data input hold time	Master mode	7.5	-	-	ns
$t_{h(SI)}$		Slave mode	3.5	-	-	ns

6.3.24 SD/SDIO MMC/eMMC card host interface (SDIO) characteristics

Unless otherwise specified, the parameters given in [Table 76](#) for the SDIO/MMC/eMMC interface are derived from tests performed under the ambient temperature, f_{PCLK2} frequency and V_{DD} supply voltage conditions summarized in [Table 14](#), with the following configuration:

- Output speed is set to $\text{OSPEEDRy}[1:0] = 10$
- Capacitive load $C = 30 \text{ pF}$ (for eMMC $C = 20 \text{ pF}$)
- Measurement points are done at CMOS levels: $0.5V_{\text{DD}}$

Refer to [Section 6.3.16: I/O port characteristics](#) for more details on the input/output characteristics.

Figure 44. SDIO high-speed mode

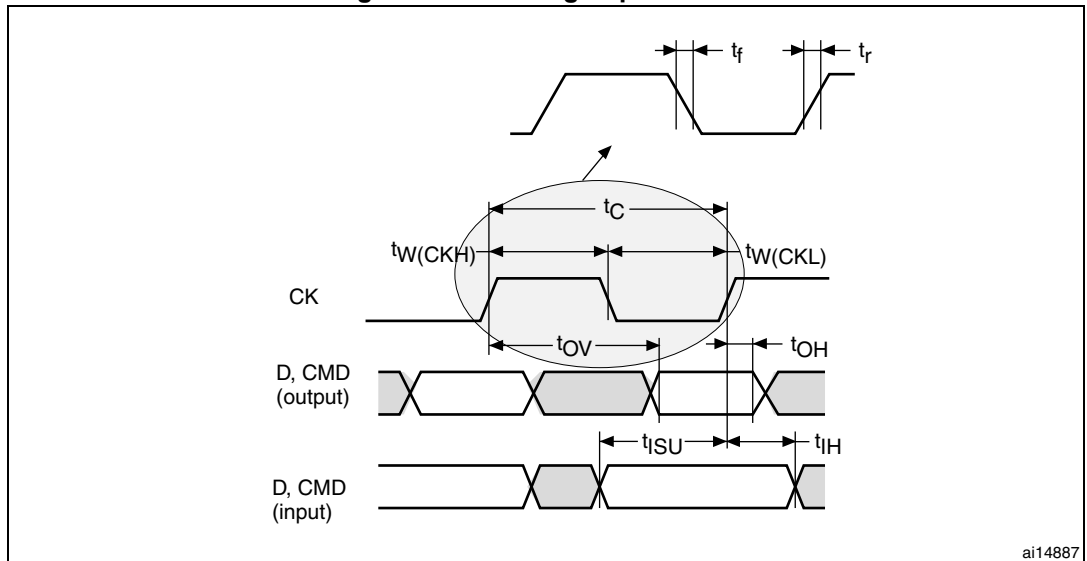
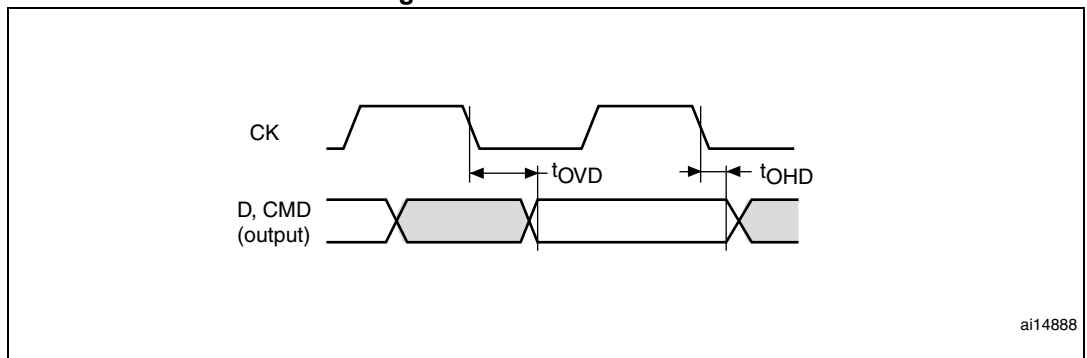


Figure 45. SD default mode

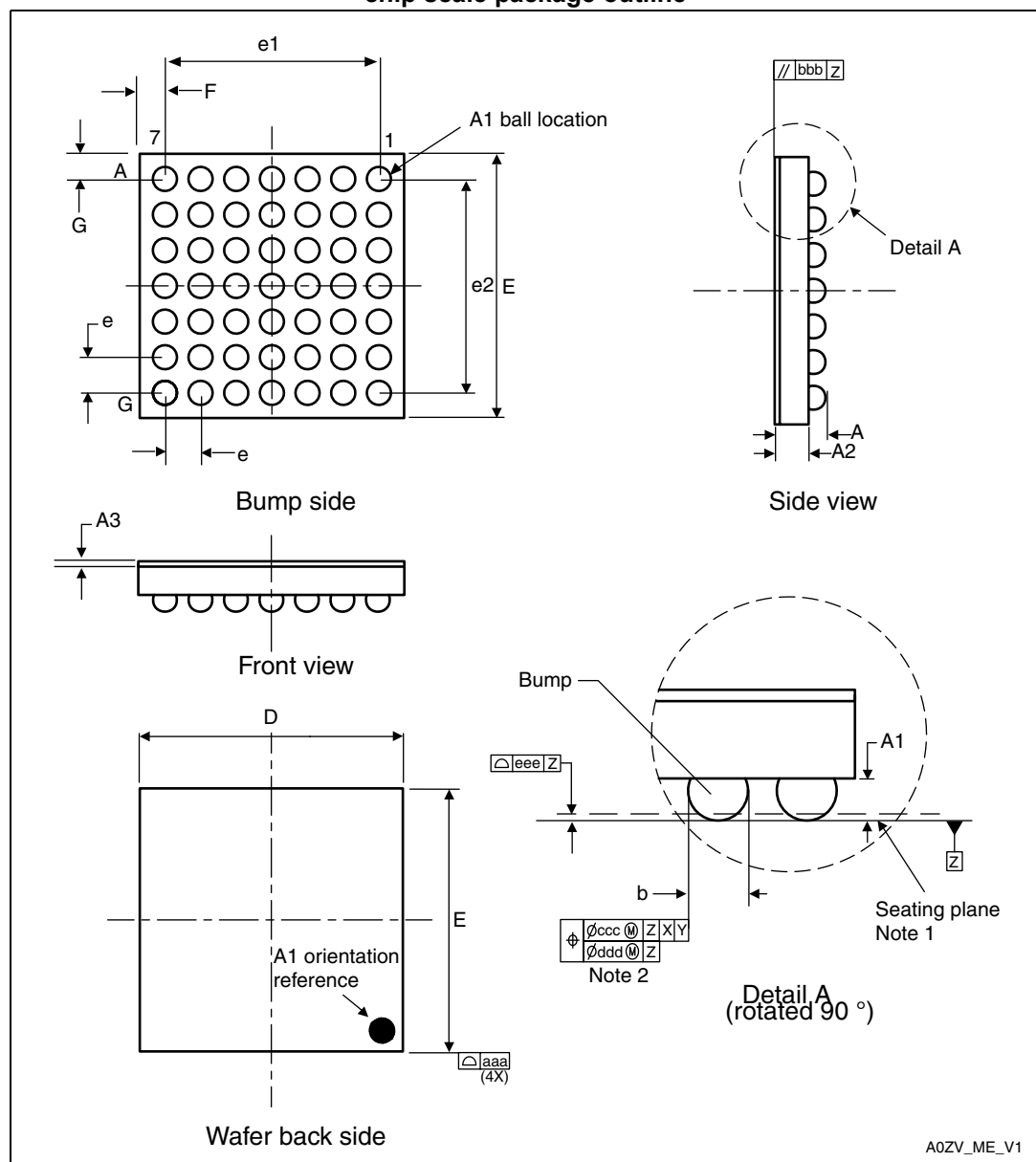


7 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK[®] packages, depending on their level of environmental compliance. ECOPACK[®] specifications, grade definitions and product status are available at: www.st.com. ECOPACK[®] is an ST trademark.

7.1 WLCSP49 package information

Figure 46. WLCSP49 - 49-ball, 2.999 x 3.185 mm, 0.4 mm pitch wafer level chip scale package outline



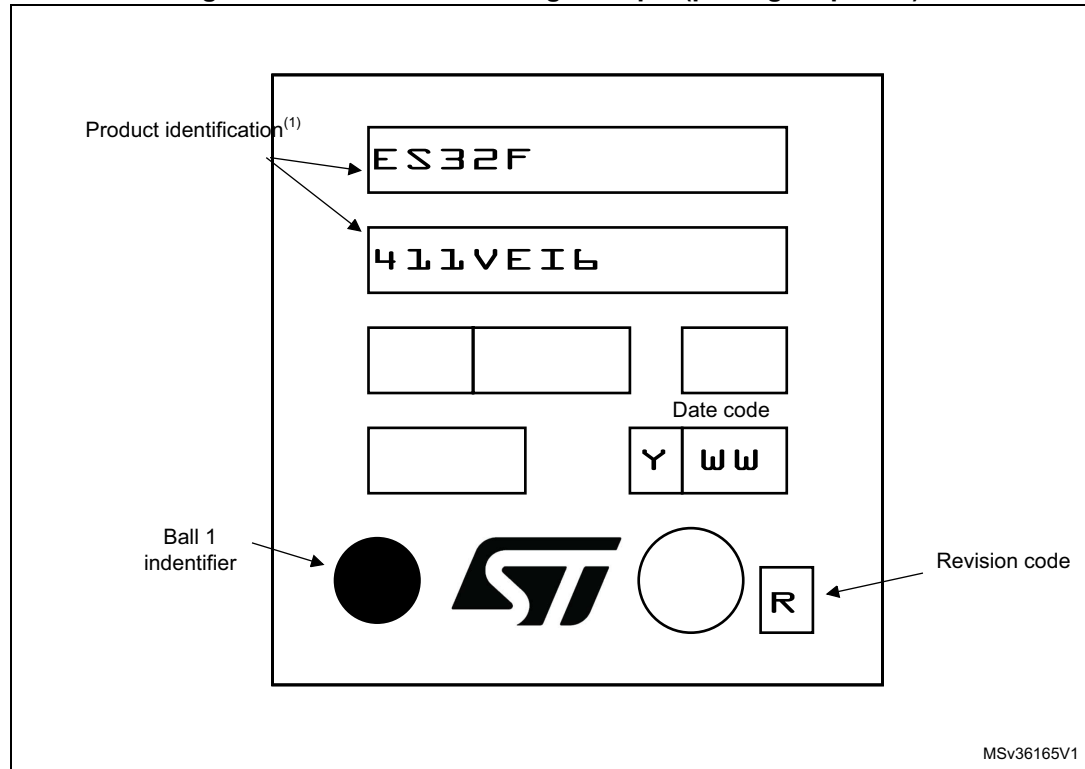
1. Drawing is not to scale.

Device marking for UFBGA100

The following figure gives an example of topside marking orientation versus ball A1 identifier location.

Other optional marking or inset/upset marks, which depend on supply chain operations, are not indicated below.

Figure 60. UFBGA100 marking example (package top view)



1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering samples to run qualification activity.

Table 88. Document revision history

Date	Revision	Changes
21-Nov-2016	5	<p>Updated:</p> <ul style="list-style-type: none"> – Features – Figure 1: Compatible board design for LQFP100 package – Figure 2: Compatible board design for LQFP64 package – Figure 3: STM32F411xC/xE block diagram – Figure 22: High-speed external clock source AC timing diagram – Figure 23: Low-speed external clock source AC timing diagram – Figure 33: I2C bus AC waveforms and measurement circuit – Figure 58: UFBGA100 - 100-ball, 7 x 7 mm, 0.50 mm pitch, ultra fine pitch ball grid array package outline – Table 2: STM32F411xC/xE features and peripheral counts – Table 8: STM32F411xC/xE pin definitions – Table 13: Thermal characteristics – Table 14: General operating conditions – From Table 20: Typical and maximum current consumption, code with data processing (ART accelerator disabled) running from SRAM - VDD = 1.7 V to Table 31: Typical and maximum current consumptions in VBAT mode – Table 35: High-speed external user clock characteristics – Table 36: Low-speed external user clock characteristics – Table 39: HSI oscillator characteristics – Table 47: Flash memory endurance and data retention – Table 51: Electrical sensitivities – Table 53: I/O static characteristics – Table 76: Dynamic characteristics: SD / MMC characteristics – Table 86: Ordering information scheme <p>Added:</p> <ul style="list-style-type: none"> – One-time programmable bytes – Table 85: Package thermal characteristics
05-Dec-2016	6	<p>Updated:</p> <ul style="list-style-type: none"> – Table 27: Typical and maximum current consumptions in Stop mode - VDD = 1.7 V – Table 28: Typical and maximum current consumption in Stop mode - VDD=3.6 V – Table 29: Typical and maximum current consumption in Standby mode - VDD= 1.7 V – Table 30: Typical and maximum current consumption in Standby mode - VDD= 3.6 V

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